

[54] PINCETTE TYPE MULTI-TESTER

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[**] Term: 14 Years

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[52] U.S. Cl. D10/78
[58] Field of Search D6/46, 47, 56, 57, 75-80, D6/102-103; 324/149, 72.5, 51, 156

[56]

References Cited

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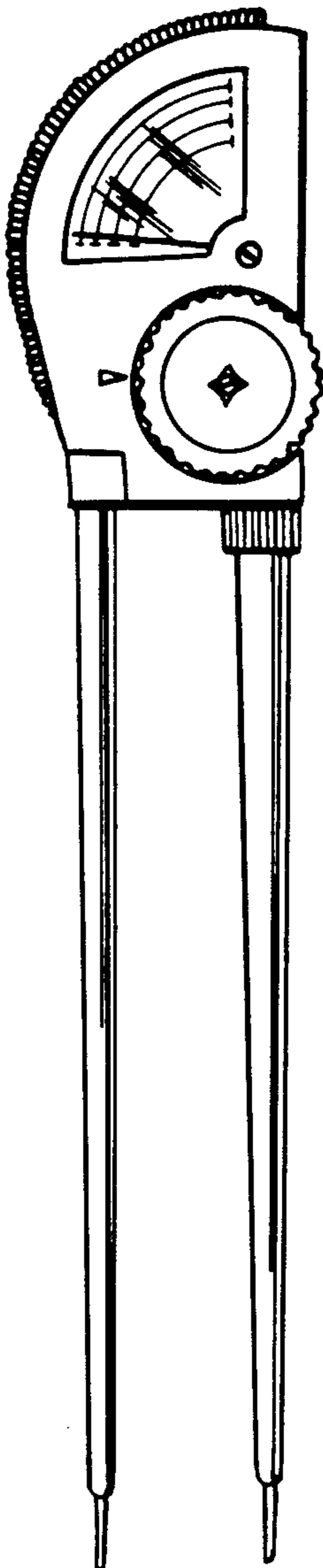
[57]

CLAIM

The ornamental design for a pincette type multi-tester, substantially as shown.

DESCRIPTION

FIG. 1 is a rear elevational view of a pincette-type multi-tester showing our new design;
FIG. 2 is a left side elevational view thereof;
FIG. 3 is a front elevational view thereof;
FIG. 4 is a right side elevational view thereof;
FIG. 5 is a top plan view thereof;
FIG. 6 is a bottom plan view thereof.



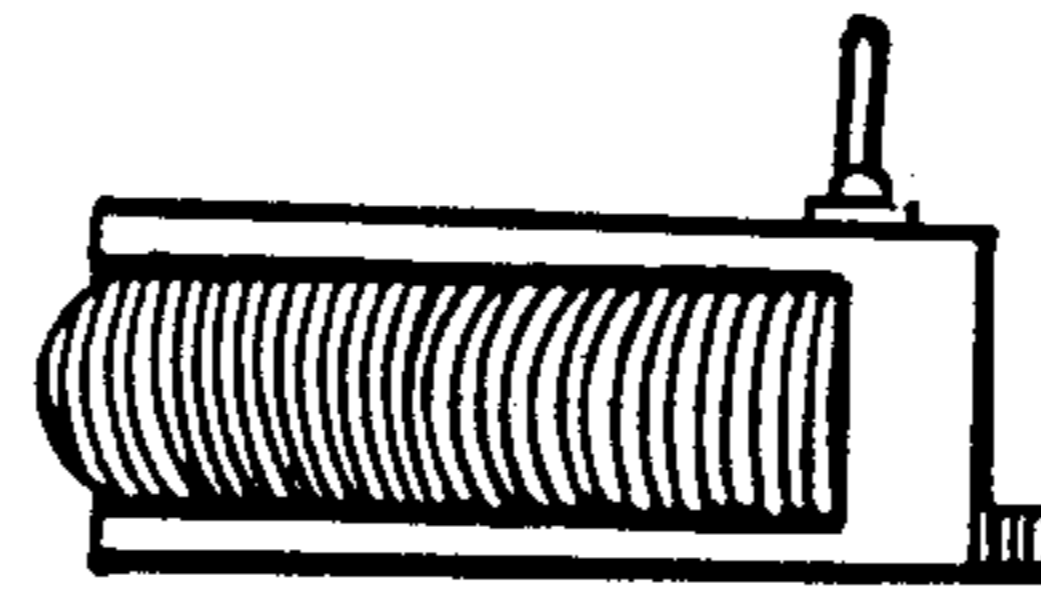


FIG. 5

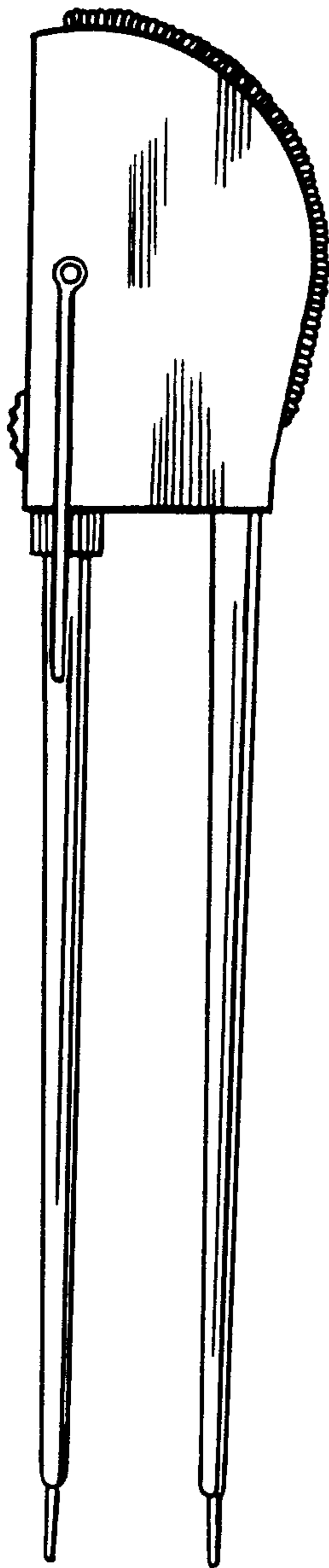


FIG. 1

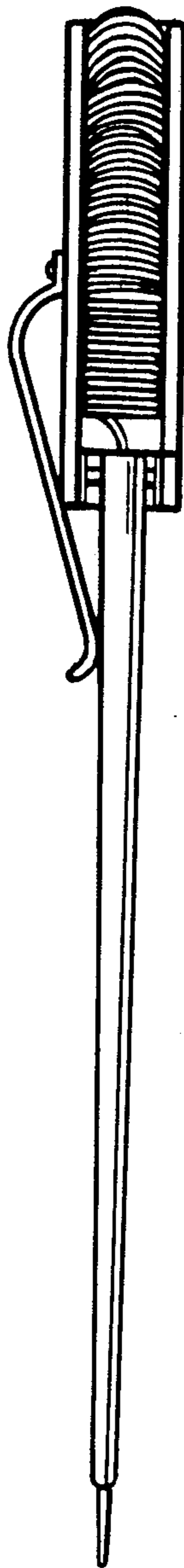


FIG. 2

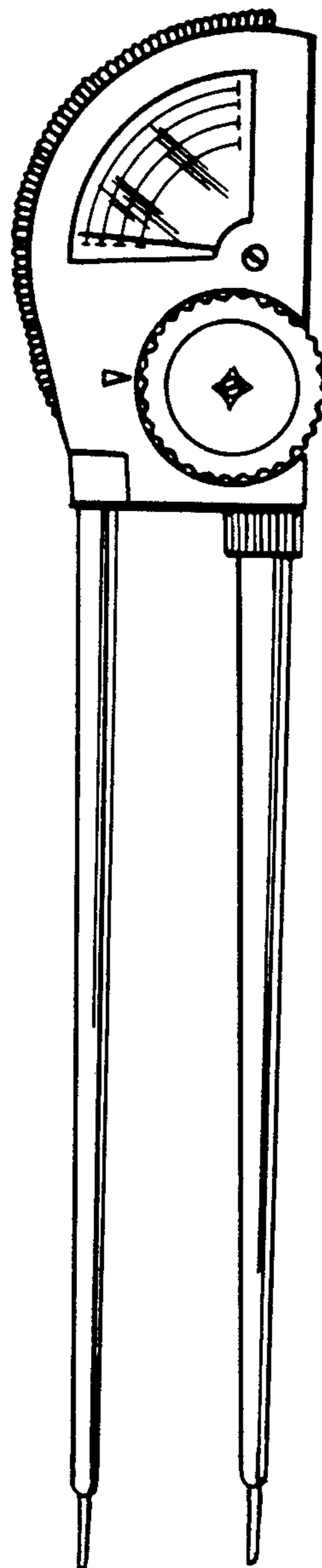


FIG. 3

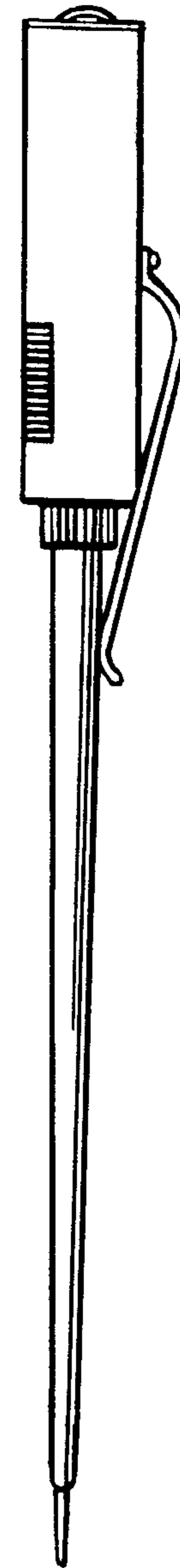


FIG. 4

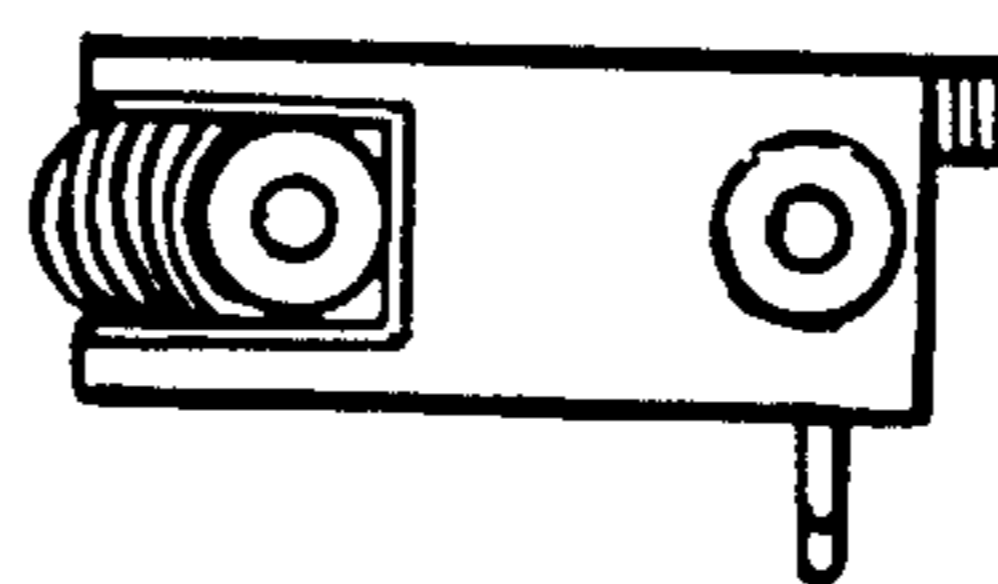


FIG. 6